



501.42867X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): I. OCHIAI, et al.
Serial No.: 10/601,531
Filed: June 24, 2003
For: ELECTRON MICROSCOPE INCLUDING APPARATUS OF X-
RAY ANALYSIS AND METHOD OF ANALYZING SPECIMENS
USING SAME

Group:

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

July 25, 2003

Sir:

The following preliminary amendments and remarks are respectfully
submitted in connection with the above-identified application.